Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/687,085	MAEDA, HIROSHI		
Examiner	Art Unit		
Stephen W. Smoot	2813		

Class	Subclass	Date	Examiner	:
438	108	1/12/2005	sws	
438	118	1/12/2005	sws	
438	126	1/12/2005	sws	
438	127	1/12/2005	sws	YI.W.Z
438	132	1/12/2005	sws	
438	601	1/12/2005	sws	
438	612	1/12/2005	sws	
438	613	1/12/2005	sws	
438	958	1/12/2005	sws	
Updated	Above	5/23/2005	sws	P.W.L.

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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			00 10		
Same as Above		5/23/2005	. W·Д· sws		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Key Words: Chip, Die, IC - Pad; Solder - Bump, Ball; Polyimide; Passivation; Fuse;	1/12/2005	J.W.Z. sws			
Chip Carrier, Package Substrate, Wiring Substrate; Flip Chip Assembly; Underfilled.	1/12/2005	S.W.S.			
Updated Above Search	5/23/2005	I.V.J.			
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	1/12/2005 & 5- 73 -05	sws L.W.J			